



FQD16N25C 250V N-Channel MOSFET

Features

- 16A, 250V, $R_{DS(on)}$ = 0.27 Ω @V_{GS} = 10 V Low gate charge (typical 41 nC)
- Low Crss (typical 68 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- RoHS Compliant

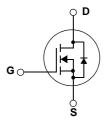


Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supplies, DC-AC converters for uninterrupted power supplies and motor controls.





Absolute Maximum Ratings

Symbol	Parameter	FQD16N25C	Units	
V _{DSS}	Drain-Source Voltage	250	V	
I _D	Drain Current - Continuous (T _C = 25°C)		16	A
	- Continuous (T _C = 100°C)	10.1	A	
I _{DM}	Drain Current - Pulsed	(Note 1)	64	A
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		432	mJ
I _{AR}	Avalanche Current (Note 1)		16	А
E _{AR}	Repetitive Avalanche Energy (Note 1)		160	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
P_{D}	Power Dissipation ($T_C = 25^{\circ}C$)		160	W
	- Derate above 25°C		1.28	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150	°C	
TL	Maximum lead temperature for soldering purposes 1/8" from case for 5 seconds	300	°C	

Thermal Characteristics

Symbol	Parameter	FQD16N25C	Units	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.78	°C/W	
$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient	110	°C/W	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQD16N25C	FQD16N25CTM	D-PAK	380mm	16mm	2,500
FQD16N25C	FQD16N25CTF	D-PAK	380mm	16mm	2,000

Electrical Characteristics $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charac	teristics	-				1
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	250			V
$\Delta BV_{DSS}/$ ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.31		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 250 V, V _{GS} = 0 V			10	μΑ
		V _{DS} = 200 V, T _C = 125°C			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Charact	eristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 8A		0.22	0.27	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D =8 A (Note 4)		10.5		S
Dynamic Cl	haracteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		830	1080	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		170	220	pF
C _{rss}	Reverse Transfer Capacitance			68	89	pF
Switching C	Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 125 V, I _D = 16A,		15	40	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		130	270	ns
t _{d(off)}	Turn-Off Delay Time			135	280	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		105	220	ns
Qg	Total Gate Charge	V _{DS} = 200 V, I _D = 16A,		41	53.5	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		5.6		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		22.7		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings	5				
I _S	Maximum Continuous Drain-Source Diode Forward Current				16	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				64	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 16 A			1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 16 A,		260		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		2.47		μС

NOTES

^{1.} Repetitive Rating : Pulse width limited by maximum junction temperature

^{2.} L = 2.7mH, I $_{AS}$ = 16A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C

^{3.} $I_{SD} \le 16A$, di/dt $\le 300A/\mu s$, $V_{DD} \le BV_{DSS,}$ Starting T_J = $25^{\circ}C$

^{4.} Pulse Test : Pulse width $\leq 300 \mu \text{s}, \, \text{Duty cycle} \leq 2\%$

^{5.} Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

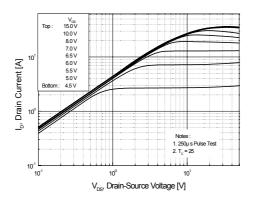
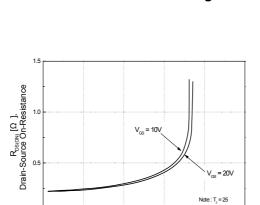


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage



I_D, Drain Current [A]

Figure 5. Capacitance Characteristics

0.0 L

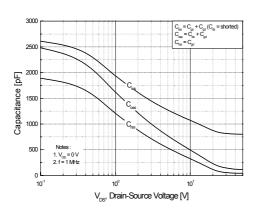


Figure 2. Transfer Characteristics

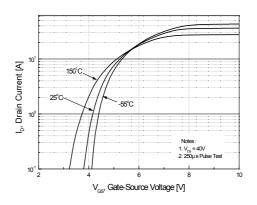


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

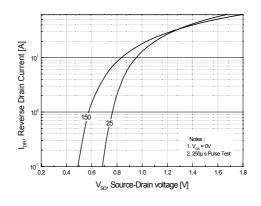
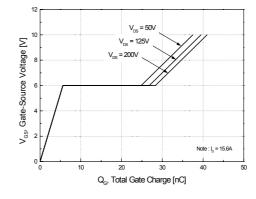


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

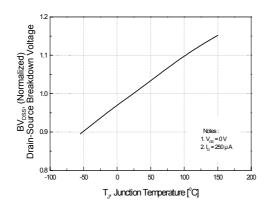


Figure 8. On-Resistance Variation vs. Temperature

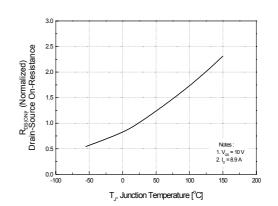
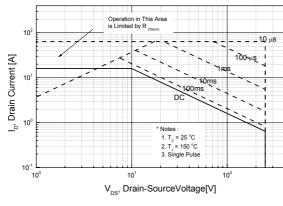


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature



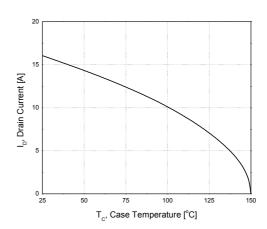
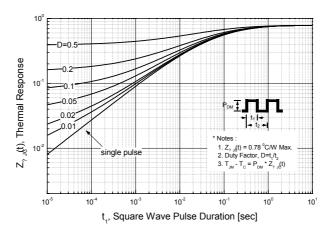
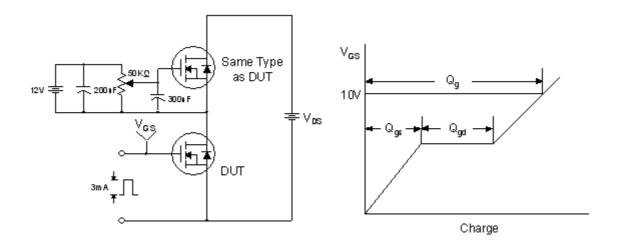


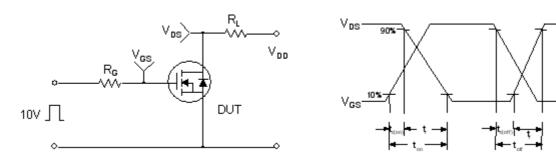
Figure 11. Transient Thermal Response Curve



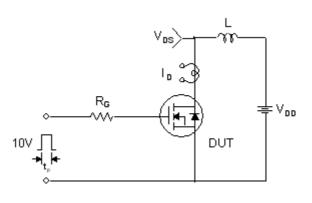
Gate Charge Test Circuit & Waveform

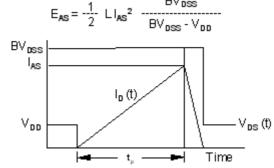


Resistive Switching Test Circuit & Waveforms

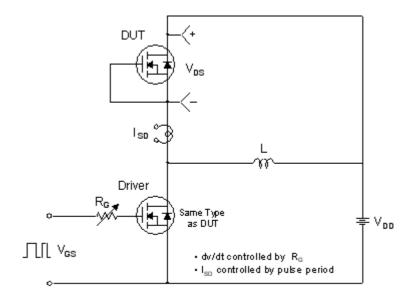


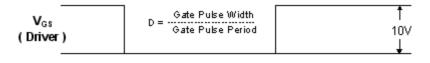
Unclamped Inductive Switching Test Circuit & Waveforms

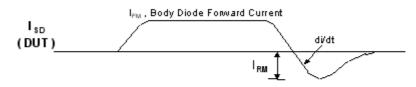


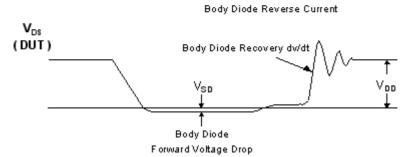


Peak Diode Recovery dv/dt Test Circuit & Waveforms





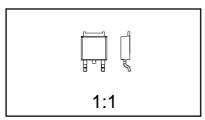




Mechanical Dimensions

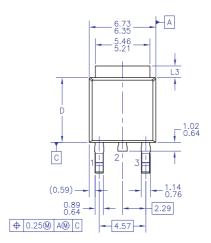
TO-252 (DPAK) (FS PKG Code 36)



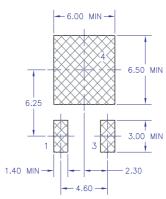


Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

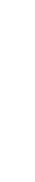
Part Weight per unit (gram): 0.33

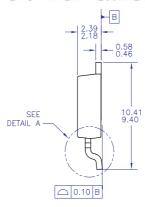


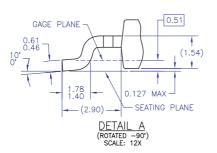
SEE NOTE D



LAND PATTERN RECOMMENDATION







- NOTES: UNLESS OTHERWISE SPECIFIED

 A) ALL DIMENSIONS ARE IN MILLIMETERS.

 B) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA & AB, DATED NOV. 1999.

 C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

 D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.

 E) DIMENSIONS L3,D,E1&D1 TABLE:

	OPTION AA	OPTION AB
L3	0.89-1.27	1.52-2.03
D	5.97-6.22	5.33-5.59
E1	4.32 MIN	3.81 MIN
D1	5.21 MIN	4.57 MIN





TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

Build it Now™ CorePLUS™ CorePOWER™ CROSSVOLT™

CTL™
Current Transfer Logic™
EcoSPARK®
EfficentMax™
EZSWITCH™ *

Fairchild®

Fairchild Semiconductor®

FACT Quiet Series™ FACT® FAST® FastvCore™ FlashWriter® * FPS™ F-PFS™ FRFET[®]
Global Power ResourceSM
Green FPS™

Green FPS™ e-Series™
GTO™
IntelliMAX™
ISOPLANAR™
MegaBuck™
MICROCOUPLER™
MicroFET™

MicroPak™ MillerDrive™ MotionMax™ Motion-SPM™ OPTOLOGIC® OPTOPLANAR®

PDP SPM™ Power-SPM™ PowerTrench® PowerXS™ Programmable Active Droop™ QFET®

QS™ Quiet Series™ RapidConfigure™

Saving our world, 1mW /W /kW at a time™ SmartMax™

SMART START™ SPM® STEALTH™ SuperFET™ SuperSOT™-3 SuperSOT™-6

SuperSOT™-6 SuperSOT™-8 SupreMOS™ SyncFET™

GENERAL
The Power Franchise®

the production of the product

SerDes"
UHC®
Ultra FRFET™
UniFET™
VCX™
VisualMax™
XS™

* EZSWITCH™ and FlashWriter[®] are trademarks of System General Corporation, used under license by Fairchild Semiconductor.

DISCL AIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Farichild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from fairchild directly or from Authorized Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Farichild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. I37

FQD16N25C Rev. A1 www.fairchildsemin.com